

-60V P-Channel Enhancement Mode MOSFET

Description

The AP120P06D uses advanced **APM-SGT₁** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 6V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = -60V$ $I_D = -120A$

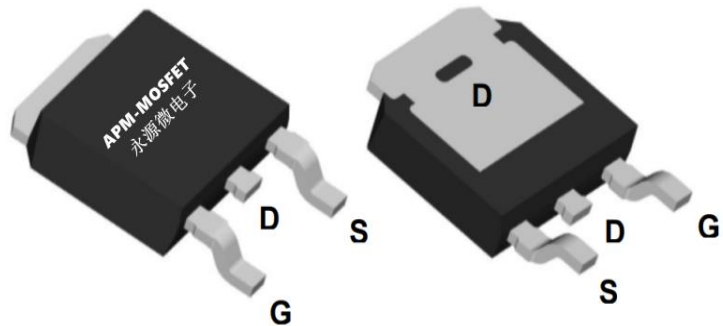
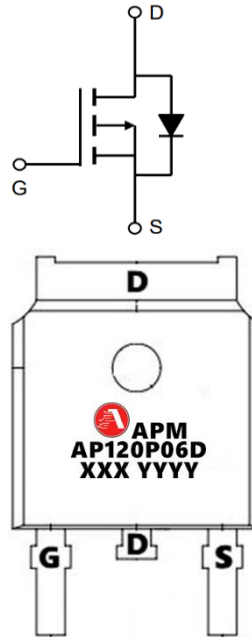
$R_{DS(ON)} < 7.2m\Omega$ @ $V_{GS} = -10V$ (Type: **5.3m Ω**)

Application

Lithium battery protection

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP120P06D	TO-252-3L	AP120P06D XXX YYYY	5000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-120	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-70	A
I_{DM}	Pulsed Drain Current ²	-360	A
EAS	Single Pulse Avalanche Energy ³	800	mJ
I_{AS}	Avalanche Current	51	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	110	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	62.5	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	0.69	$^\circ C/W$

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Electrical Characteristics (T_c=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250uA	-60	-68	---	V
ΔBVDSS/ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C, I _D =-1mA	---	-0.035	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =-10V, I _D =-20A	---	5.0	6.5	mΩ
		V _{GS} =-4.5V, I _D =-15A	---	7.2	10	
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.2	-2.0	-2.5	V
ΔVGS(th)	V _{GS(th)} Temperature Coefficient		---	4.28	---	mV/°C
IDSS	Drain-Source Leakage Current	V _{DS} =-60V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =-60V, V _{GS} =0V, T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	2.0	---	Ω
Q _g	Total Gate Charge (-4.5V)	V _{DS} =-30V, V _{GS} =-10V I _D =-15A	---	80.2	---	nC
Q _{gs}	Gate-Source Charge		---	15.2	---	
Q _{gd}	Gate-Drain Charge		---	11	---	
Td(on)	Turn-On Delay Time	V _{DD} =-30V, V _{GS} =-10V, R _G =3Ω, I _D =-15A	---	4.5	---	ns
T _r	Rise Time		---	2.5	---	
Td(off)	Turn-Off Delay Time		---	14.5	---	
T _f	Fall Time		---	3.5	---	
C _{iss}	Input Capacitance	V _{DS} =-30V, V _{GS} =0V, f=1MHz	---	5403	---	pF
C _{oss}	Output Capacitance		---	941	---	
C _{rss}	Reverse Transfer Capacitance		---	48	---	
I _s	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	-120	A
ISM	Pulsed Source Current ^{2,5}		---	---	-480	A
VSD	Diode Forward Voltage ²	V _{GS} =0V, I _S =-1A, T _J =25°C	---	---	-1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD =-48V,VGS =-10V,L=0.1mH,IAS =-51A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

Typ. output characteristics

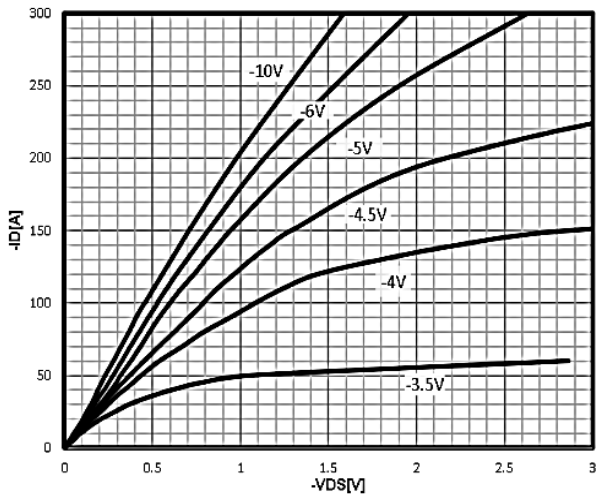


Figure 1. Typ. output characteristics

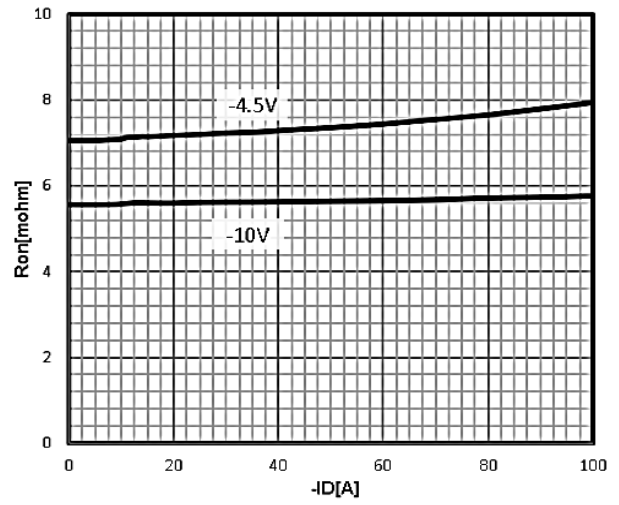


Figure 2. Typ. drain-source on

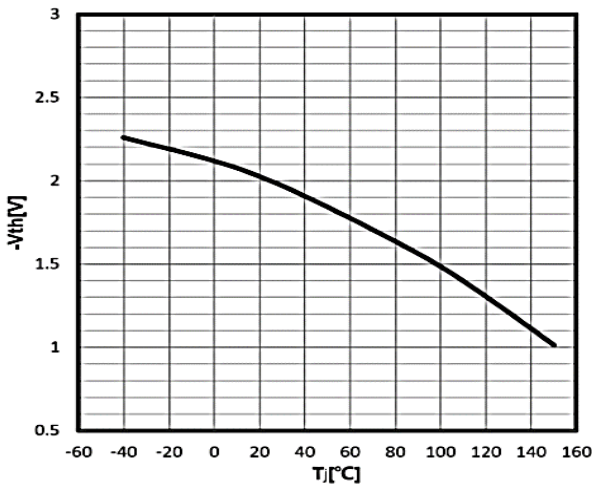


Figure 3. Gate Threshold Voltage

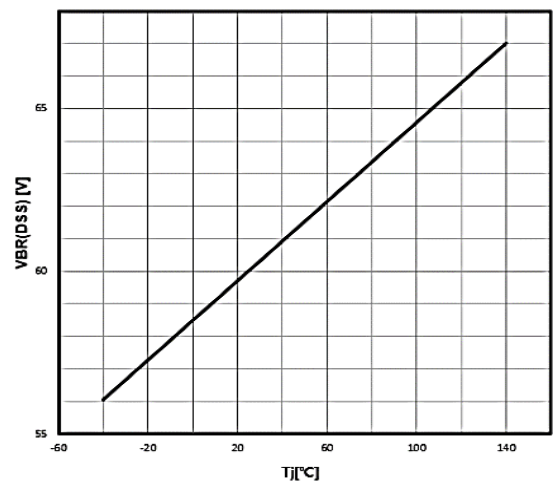


Figure 4. Drain-source breakdown voltage

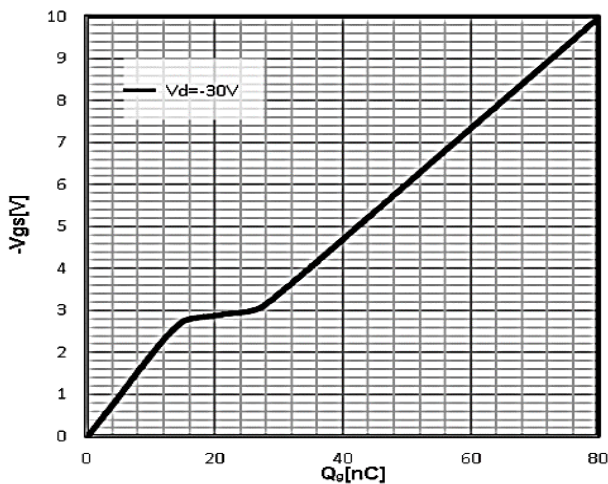


Figure 5. Typ. gate charge

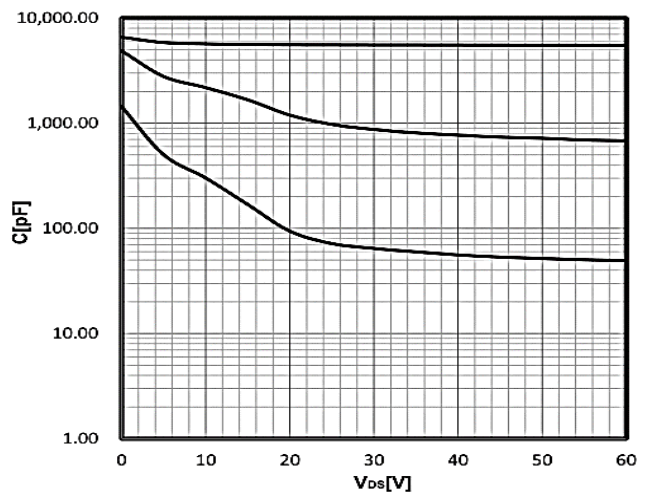


Figure 6. Typ. capacitances



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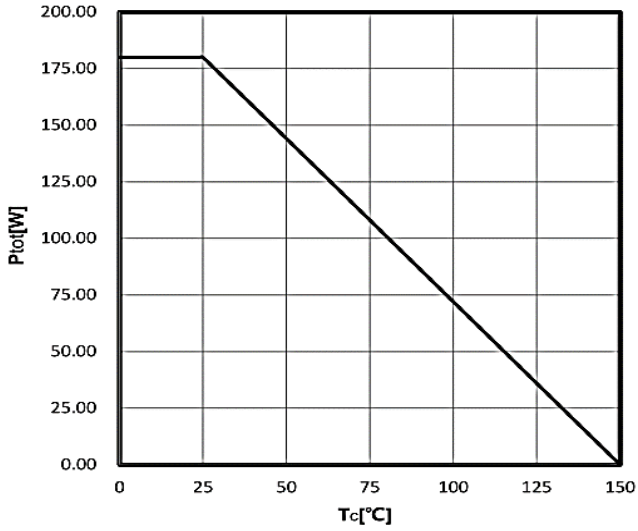


Figure 7. Power Dissipation

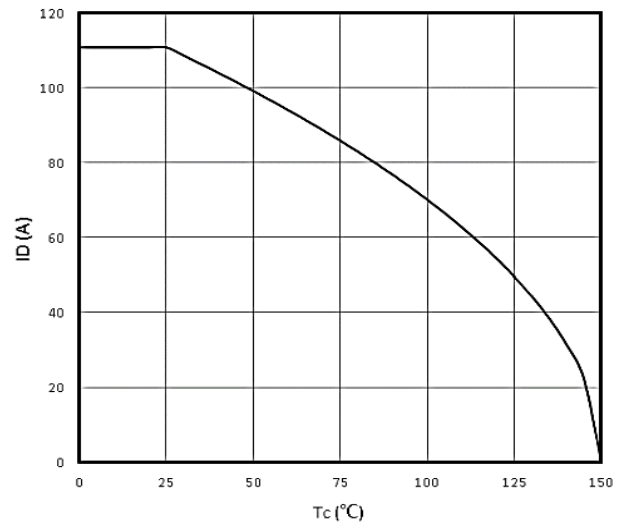


Figure 8. Maximum Drain Current

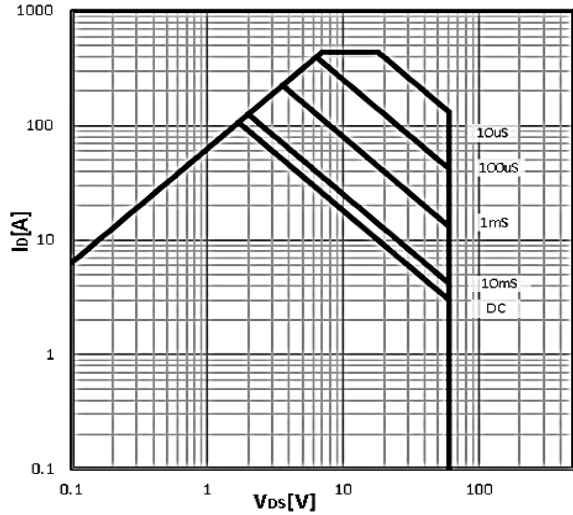


Figure 9. Safe operating area

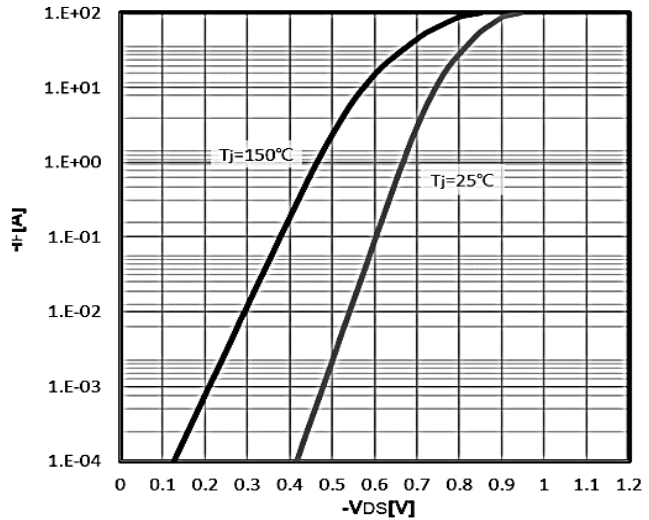


Figure 10. Body Diode Forward Voltage Variation

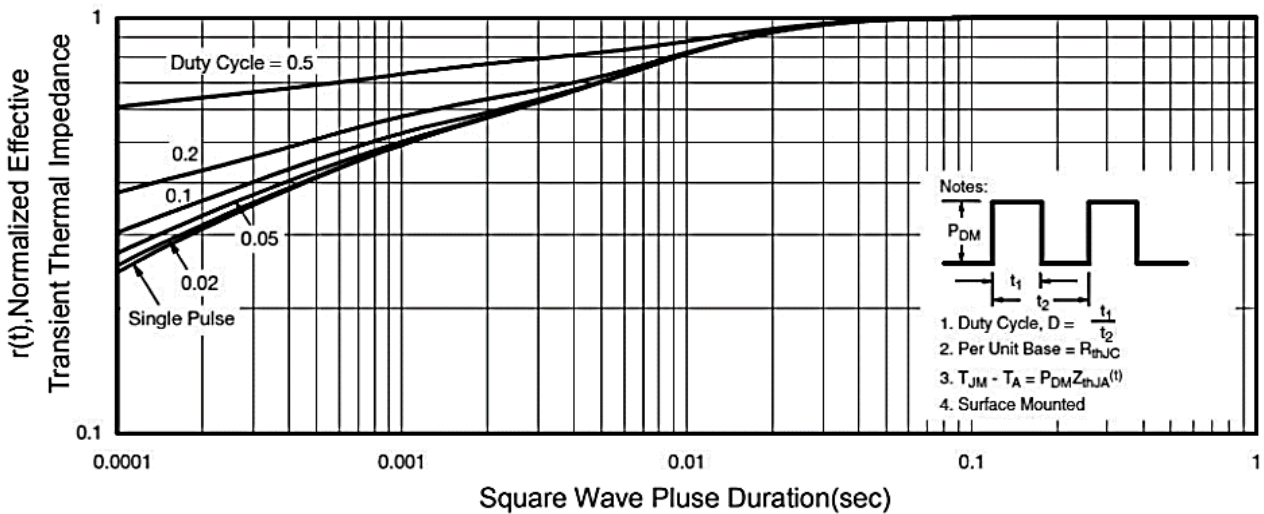
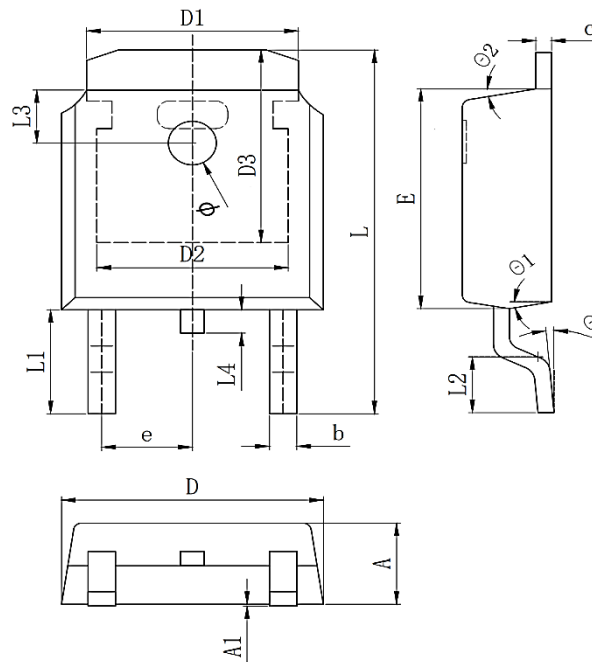


Figure 11. Max. transient thermal impedance

Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ1	5°		10°
θ2	5°		10°

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Edition	Date	Change
REV1.0	2023/2/31	Initial release

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